Patent

THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT(S):

Joseph C. Marron

APPLN. NO:

10/601,802

CONFIRMATION NO.:

unknown

FILED:

23 June 2003

ART UNIT:

unknown

TITLE:

MULTI-STAGE DATA PROCESSING FOR FREQUENCY-

SCANNING INTERFEROMETER

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P. O. Box 1450 Alexandria, Virginia 22313-1450

Dear Sir:

Here are copies of references that may be relevant to the examination of this application. These references are listed on attached Forms PTO-SB/08A and 08B.

Priority is claimed to Provisional Application Nos. 60/391,004 filed 24 June 2002 entitled "System For Processing Multi-Wavelength Interferometer Data".

Other commonly assigned applications relating to the same general field of technology are as follows:

- US Patent Application No. 10/446,012 entitled "Tunable Laser System Having An Adjustable External Cavity",
- US Patent Application No. 10/465,181 entitled "Common-path Frequency-scanning Interferometer",
- US Patent Application No. 10/610,235 entitled "Frequencyscanning Interferometer With Non-specular Reference Surface", and
- US Patent Application No. 10/610,236 entitled "Interferometer System of Compact Configuration".

The Examiner's attention is also directed to the Background portion of the application for a discussion of the state of the art in which the invention was made.

For any questions on this art or the application, the Examiner is invited to call applicant's representative at the number listed below.

Respectfully submitted,

- Sho Dom

Thomas B. Ryan Reg. No. 31,659 Eugene Stephens & Associates 56 Windsor Street Rochester, New York 14605

Phone: (585) 232-7700

Dated:

AUG 29 2003

I hereby certify that this correspondence is being deposited with the United States
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Application Number	10/601,802		
Filing Date	23 June 2003		
First Named Inventor	Joseph C. Marron		
Group Art Unit	unknown		
Examiner Name			
Attorney Docket Number	Marron 06/03-2		

U.S. PATENT DOCUMENTS						
Examiner Cite Initials* No.1			Code ²	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	U.S. Classification (Primary Class/Subclass)
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Examiner Initials*	Cite	Fore	ign Patent Do	cument	Name of Patentee	Name of Patentee or Applicant		of Publication of ed Document	Pages, Columns, Lines Where Relevant	
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, indication of the year of the reign of the Emperor must precede the serial number of the document. ⁵ Kind of document by the appropriate symbols as indicated on the document under the WIPO Standard ST.16, if possible. ⁵ Applicant is to place a check mark here if English language Translation is attached.

PTO/SB/08B (10-96)

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ENT & TRA					Examiner Name	Unknown
	Sheet	2	of	4	Attorney Docket Number	Marron 06/03-2

		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
Examiner	Cite	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the	
Initials*	No.1	item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	T ²
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Exan Signa	_	Date Considered	
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		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
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Signature	Considered

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Sheet 4 of 4

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